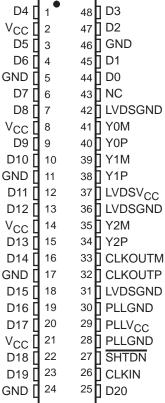
- Qualified for Automotive Applications
- 21:3 Data Channel Compression at up to
 1.36 Gigabits per Second Throughput
- Suited for Point-to-Point Subsystem Communication With Very Low EMI
- 21 Data Channels Plus Clock in Low-Voltage TTL and 3 Data Channels Plus Clock Out Low-Voltage Differential
- Operates From a Single 3.3-V Supply and 250 mW (Typ)
- 5-V Tolerant Data Inputs
- 'LVDS95 Has Rising Clock Edge Triggered Inputs
- Bus Pins Tolerate 6-kV HBM ESD
- Packaged in Thin Shrink Small-Outline Package With 20 Mil Terminal Pitch
- Consumes <1 mW When Disabled
- Wide Phase-Lock Input Frequency Range 20 MHz to 68 MHz
- No External Components Required for PLL
- Inputs Meet or Exceed the Requirements of ANSI EIA/TIA-644 Standard
- Industrial Temperature Qualified

 $T_A = -40^{\circ}C$ to $85^{\circ}C$

Replacement for the National DS90CR215

DGG PACKAGE (TOP VIEW)



description/ordering information

The SN65LVDS95 LVDS serdes (serializer/deserializer) transmitter contains three 7-bit parallel-load serial-out shift registers, a 7× clock synthesizer, and four low-voltage differential signaling (LVDS) line drivers in a single integrated circuit. These functions allow 21 bits of single-ended LVTTL data to be synchronously transmitted over 4 balanced-pair conductors for receipt by a compatible receiver, such as the SN65LVDS96.

ORDERING INFORMATION†

TA	PACKAGE [‡]		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	TSSOP - DGG	Tape and reel	SN65LVDS95DGGRQ1	65LVDS95Q

[†] For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



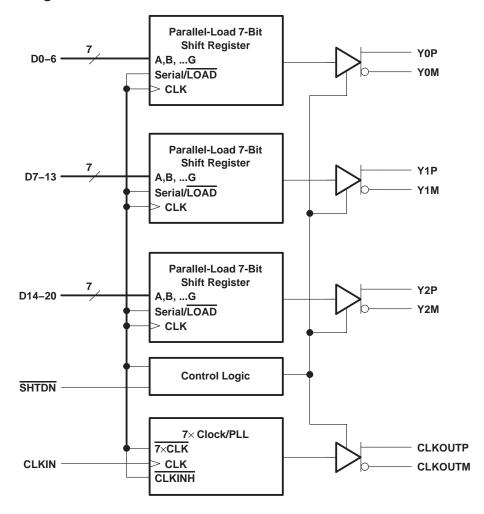
[‡] Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.

description/ordering information (continued)

When transmitting, data bits D0 through D20 are each loaded into registers of the SN65LVDS95 on the rising edge of the input clock signal (CLKIN). The frequency of CLKIN is multiplied seven times and then used to serially unload the data registers in 7-bit slices. The three serial streams and a phase-locked clock (CLKOUT) are then output to LVDS output drivers. The frequency of CLKOUT is the same as the input clock, CLKIN.

The SN65LVDS95 requires no external components and little or no control. The data bus appears the same at the input to the transmitter and output of the receiver with data transmission transparent to the user(s). The only user intervention is the possible use of the shutdown/clear (SHTDN) active-low input to inhibit the clock and shut off the LVDS output drivers for lower power consumption. A low level on this signal clears all internal registers to a low level.

functional block diagram





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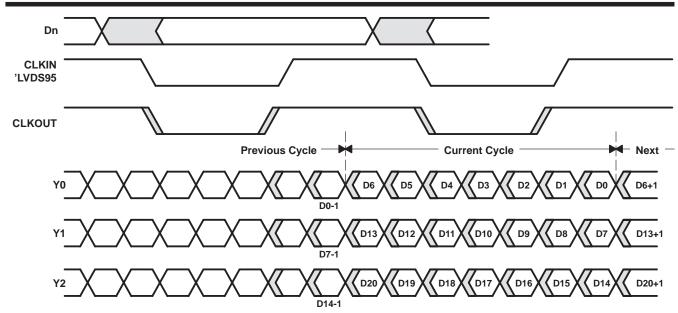
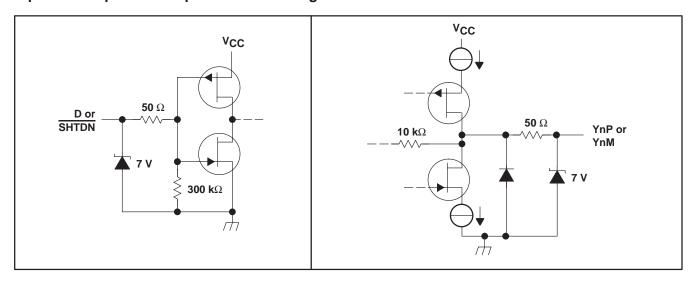


Figure 1. 'LVDS95 Load and Shift Sequences

equivalent input and output schematic diagrams



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V _{CC} (see Note	1)	0.5 V to 4 V
Voltage range at any output terminal,	V _O	
Voltage range at any input terminal, V	1	
Electrostatic discharge (see Note 2):	Bus pins (Class 3A)	6 KV
	Bus pins (Class 2B)	
	All pins (Class 3A)	6 KV
	All pins (Class 2B)	
Continuous total power dissipation .		(see Dissipation Rating Table)
Operating free-air temperature range,	T _A	
Storage temperature range, T _{stg}		–65°C to 150°C
		ds 260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C	DERATING FACTOR [‡]	T _A = 70°C	T _A = 85°C
	POWER RATING	ABOVE T _A = 25°C	POWER RATING	POWER RATING
DGG	1316 mW	13.1 mW/°C	724 mW	526 mW

[‡]This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	3	3.3	3.6	V
High-level input voltage, V _{IH}	2			V
Low-level input voltage, V _{IL}			0.8	V
Differential load impedance, Z _L	90		132	Ω
Operating free-air temperature, T _A	-40		85	°C



NOTES: 1. All voltage values are with respect to the GND terminals.

^{2.} This rating is measured using MIL-STD-883C Method, 3015.7.

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electrical characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
V _{IT}	Input voltage threshold			1.4		V
IVODI	Differential steady-state output voltage magnitude		247		454	
Δ V _{OD}	Change in the steady-state differential output voltage magnitude between opposite binary states	R_L = 100 Ω, See Figure 3			50	mV
Voc(ss)	Steady-state common-mode output voltage	Can Figure 2	1.125		1.375	V
VOC(PP)	Peak-to-peak common-mode output voltage	See Figure 3		80	150	mV
lн	High-level input current	VIH = VCC			20	μΑ
I _{IL}	Low-level input current	V _{IL} = 0 V			±10	μΑ
	Object since it autout assessed	V _O Y = 0 V			±24	mA
los	Short-circuit output current	V _{OD} = 0 V			±12	mA
loz	High-impedance state output current	$V_O = 0 V \text{ to } V_{CC}$			±10	μΑ
		Disabled, all inputs at GND			280	μΑ
ICC(AVG)	Quiescent current (average)	Enabled, R _L = 100 Ω (4 places), Worst-case pattern (see Figure 4), t _C = 15.38 ns		85	110	mA
Ci	Input capacitance			3		pF

[†] All typical values are $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements

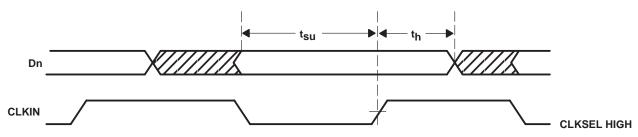
			NON	14 A V	
		MIN	NOM	MAX	UNIT
t _C	Input clock period	14.7	t _C	50	ns
t _W	High-level input clock pulse width duration	0.4t _C		0.6t _C	ns
t _t	Input signal transition time			5	ns
t _{su}	Data setup time, D0 through D27 before CLKIN↑ ('95) (see Figure 2)	3			ns
th	Data hold time, D0 through D27 after CLKIN↑ ('95) (see Figure 2)	1.5			ns

switching characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t ₀	Delay time, CLKOUT serial bit position 0		-0.20	0	0.20	ns
t ₁	Delay time, CLKOUT↑ serial bit position 1		1/7t _C -0.20		1/7t _C +0.20	ns
t ₂	Delay time, CLKOUT↑ serial bit position 2		2/7t _C -0.20		2/7t _C +0.20	ns
t ₃	Delay time, CLKOUT↑ serial bit position 3	$t_C = 15.38 \text{ ns } (\pm 0.2\%),$	3/7t _C -0.20		3/7t _C +0.20	ns
t ₄	Delay time, CLKOUT↑ serial bit position 4	Input clock jitter < 50 ps‡, See Figure 5	4/7t _C -0.20		4/7t _C +0.20	ns
t ₅	Delay time, CLKOUT↑ serial bit position 5	1	5/7t _C -0.20		5/7t _C +0.20	ns
t ₆	Delay time, CLKOUT↑ serial bit position 6		6/7t _C -0.20		6/7t _C +0.20	ns
tsk(o)	Output skew, t _n -n/7 t _C		-0.20		0.20	ns
t ₇	Delay time, CLKIN↑ to CLKOUT↑	t_C = 15.38 ns (±0.2%), Input clock jitter < 50 ps [‡] , See Figure 5		4.2		ns
	Output also to make "the &	$t_{\rm C}$ = 15.38 ns + 0.75 sin(2 π 500E3t) \pm 0.05 ns, See Figure 6		±80		ps
∆tC(O)	Output clock cycle-to-cycle jitter§	$t_{\rm C}$ = 15.38 ns + 0.75 sin(2 π 2E6t) ±0.05 ns, See Figure 6	±300			ps
t _W	High-level output clock pulse duration			4/7 t _C		ns
t _t	Differential output voltage transition time (t _r or t _f)	See Figure 3	260	700	1500	ps
t _{en}	Enable time, SHTDN↑ to phase lock (Yn valid)	See Figure 7		1		ms
^t dis	Disable time, SHTDN↓ to off-state (CLKOUT low)	See Figure 8		250		ns

[†] All typical values are $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

PARAMETER MEASUREMENT INFORMATION



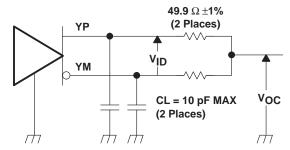
NOTE: All input timing is defined at 1.4 V on an input signal with a 10% to 90% rise or fall time of less than 5 ns.

Figure 2. Setup and Hold Time Definition

^{‡ |}Input clock jitter| is the magnitude of the change in the input clock period.

[§] The output clock jitter is the change in the output clock period from one cycle to the next cycle observed over 15,000 cycles.

PARAMETER MEASUREMENT INFORMATION



NOTE: The lumped instrumentation capacitance for any single ended voltage measurement is less than or equal to 10 pF. When making measurements at YP or YM, the complementary output shall be similarly loaded.

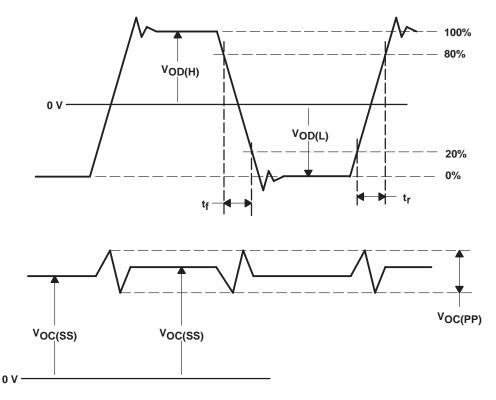


Figure 3. Test Load and Voltage Definitions for LVDS Outputs

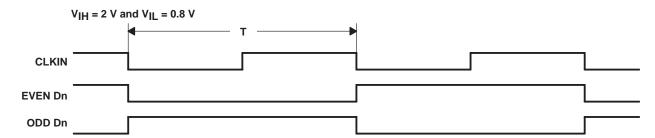


Figure 4. Worst-Case[‡] Power Test Pattern

[‡] The worst-case test pattern produces nearly the maximum switching frequency for all of the LV-TTL outputs.



PARAMETER MEASUREMENT INFORMATION

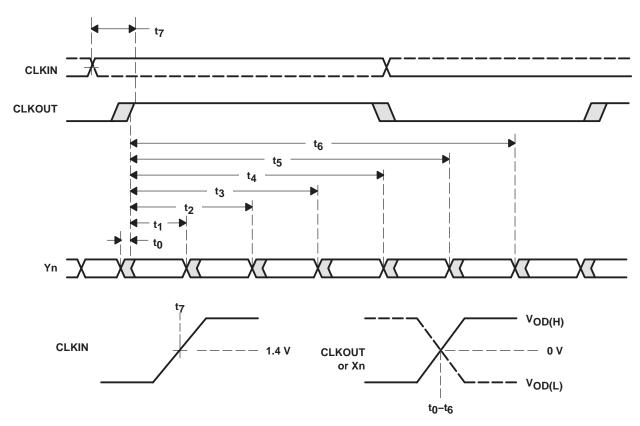


Figure 5. Timing Definitions

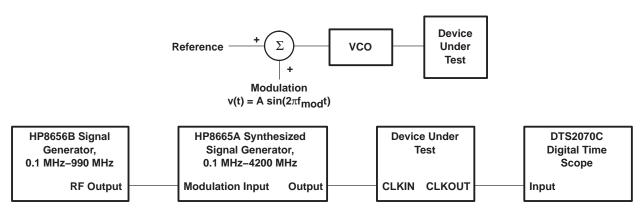


Figure 6. Clock Jitter Test Setup

PARAMETER MEASUREMENT INFORMATION

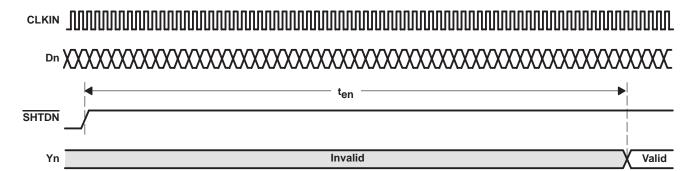


Figure 7. Enable Time Measurement Definition

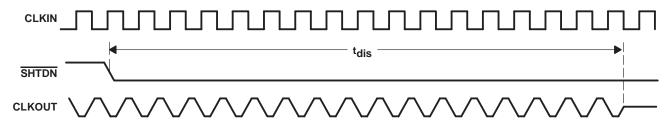


Figure 8. Disable Time Measurement Definition

TYPICAL CHARACTERISTICS

WORST-CASE SUPPLY CURRENT vs

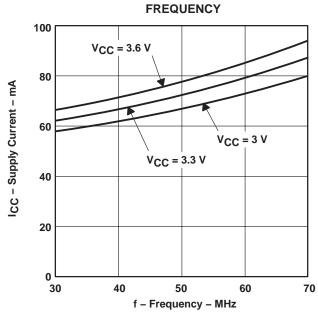


Figure 9



APPLICATION INFORMATION

16-bit bus extension

In a 16-bit bus application (Figure 10), TTL data and clock coming from bus transceivers that interface the backplane bus arrive at the Tx parallel inputs of the LVDS serdes transmitter. The clock associated with the bus is also connected to the device. The on-chip PLL synchronizes this clock with the parallel data at the input. The data is then multiplexed into three different line drivers which perform the TTL to LVDS conversion. The clock is also converted to LVDS and presented to a separate driver. This synchronized LVDS data and clock at the receiver, which recovers the LVDS data and clock, performs a conversion back to TTL. Data is then demultiplexed into a parallel format. An on-chip PLL synchronizes the received clock with the parallel data, and then all are presented to the parallel output port of the receiver.

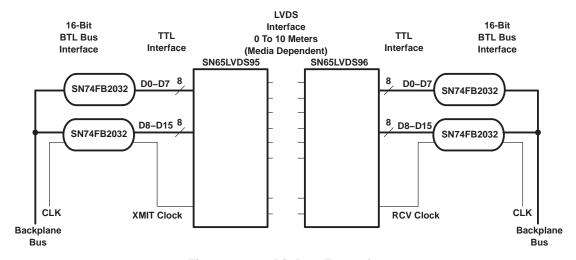


Figure 10. 16-Bit Bus Extension

16-bit bus extension with parity

In the previous application we did not have a checking bit that would provide assurance that the data crosses the link. If we add a parity bit to the previous example, we would have a diagram similar to the one in Figure 11. The device following the SN74FB2032 is a low cost parity generator. Each transmit-side transceiver/parity generator takes the LVTTL data from the corresponding transceiver, performs a parity calculation over the byte, and then passes the bits with its calculated parity value on the parallel input of the LVDS serdes transmitter. Again, the on-chip PLL synchronizes this transmit clock with the eighteen parallel bits (16 data + 2 parity) at the input. The synchronized LVDS data/parity and clock arrive at the receiver.

The receiver performs the conversion from LVDS to LVTTL and the transceiver/parity generator performs the parity calculations. These devices compare their corresponding input bytes with the value received on the parity bit. The transceiver/parity generator will assert its parity error output if a mismatch is detected.



APPLICATION INFORMATION

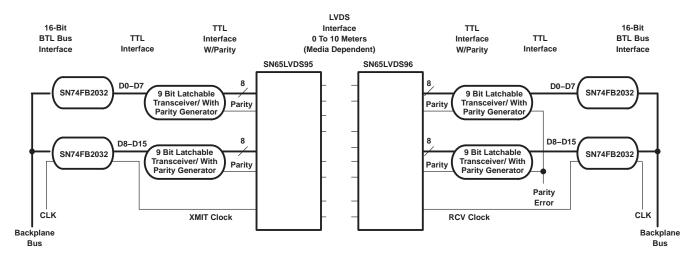


Figure 11. 16-Bit Bus Extension With Parity

low cost virtual backplane transceiver

Figure 12 represents LVDS serdes in an application as a virtual backplane transceiver (VBT). The concept of a VBT can be achieved by implementing individual LVDS serdes chipsets in both directions of subsystem serialized links.

Depending on the application, the designer will face varying choices when implementing a VBT. In addition to the devices shown in Figure 12, functions such as parity and delay lines for control signals could be included. Using additional circuitry, half-duplex or full-duplex operation can be achieved by configuring the clock and control lines properly.

The designer may choose to implement an independent clock oscillator at each end of the link and then use a PLL to synchronize LVDS serdes's parallel I/O to the backplane bus. Resynchronizing FIFOs may also be required.

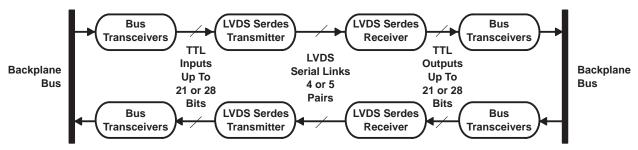


Figure 12. Virtual Backplane Transceiver



10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN65LVDS95DGGRQ1	ACTIVE	TSSOP	DGG	48	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	65LVDS95Q	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF SN65LVDS95-Q1:



PACKAGE OPTION ADDENDUM

10-Dec-2020

• Catalog: SN65LVDS95

● Enhanced Product: SN65LVDS95-EP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications



SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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